

## **Immunity of Electronic Devices**

## Short description

Both the integration density of integrated circuits and their internal processing speed continue to rise, which also entails a higher susceptibility in terms of EMC. Fast disturbance pulses which were not even perceived by slower ICs in the past may now lead to serious trouble. Immunity tests on individual IC pins show ways in which even more robust ICs can be manufactured in the future despite the increasing density of integration.